Search Notes



Application	/Control	No
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Applicant(s)/Patent Under Reexamination

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Examiner

Art Unit

Hsieh, Ping Y

2618

SEARCHED

Class	Subclass	Date	Examiner
455	76, 85, 86, 87, 118, 147, 148, 165.1, 183.1, 323, 324	4/26/10	PH

SEARCH NOTES		
es	Date	Examine
	4/00/40	D. I

Search Notes	Date	Examiner
Text search in EAST (see search history)	4/26/10	PH
PLUS search	1/28/08	PH
Consulted with Yuwen Pan, Wen Huang	11/12/08	PH

INTERFERENCE SEARCH

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